ON Semiconductor®

FDMC86160-SN00365

N-Channel Shielded Gate PowerTrench® MOSFET
100 V, 43 A, 14 mΩ

Features

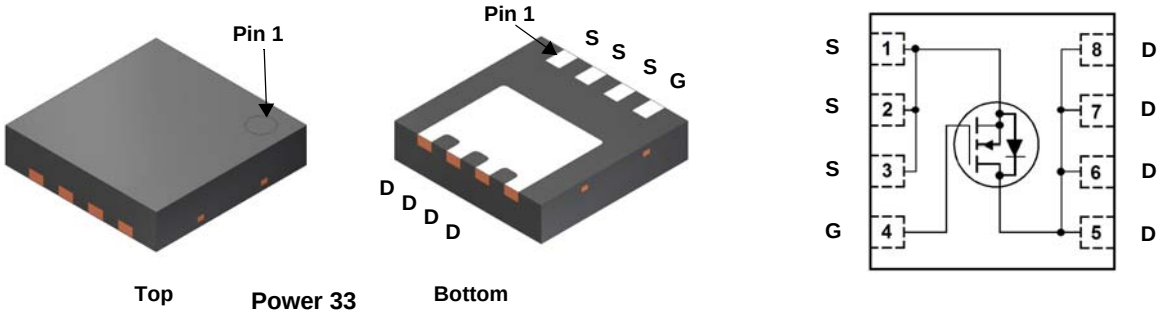
- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 14 mΩ at V_{GS} = 10 V, I_D = 9 A
- Max $r_{DS(on)}$ = 23 mΩ at V_{GS} = 6 V, I_D = 7 A
- High performance technology for extremely low $r_{DS(on)}$
- BVDSS Screen for 105V Minimum at Final Test(Note 5)
- Termination is Lead-free and RoHS Compliant

General Description

This N-Channel MOSFET is produced using ON Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance. This device is well suited for applications where ulta low $R_{DS\ (on)}$ is required in small spaces such as High performance VRM, POL and orring functions.

Applications

- Bridge Topologies
- Synchronous Rectifier



Top Power 33 Bottom

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter				Ratings	Units
V_{DS}	Drain to Source Voltage				100	V
V_{GS}	Gate to Source Voltage				±20	V
I_D	Drain Current	-Continuous	T_C = 25 °C		43	A
		-Continuous	T_A = 25 °C	(Note 1a)	9	
		-Pulsed		(Note 4)	50	
E_{AS}	Single Pulse Avalanche Energy			(Note 3)	181	mJ
P_D	Power Dissipation		T_C = 25 °C		54	W
	Power Dissipation		T_A = 25 °C	(Note 1a)	2.3	
T_J, T_{STG}	Operating and Storage Junction Temperature Range				-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	2.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	53	

Package Marking and Ordering Information

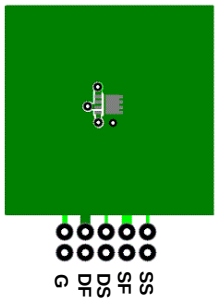
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC86160-365	FDMC86160-SN00365	Power33	13 ”	12 mm	3000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

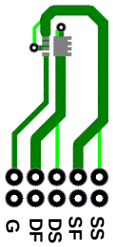
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250 μA, V_{GS} = 0 V	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		73		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 80 V, V_{GS} = 0 V			1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±20 V, V_{DS} = 0 V			±100	nA
On Characteristics						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250 μA	2	2.9	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		-9		mV/°C
$r_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10 V, I_D = 9 A		11.2	14	mΩ
		V_{GS} = 6 V, I_D = 7 A		16	23	
		V_{GS} = 10 V, I_D = 9 A, T_J = 125 °C		21	26	
g_{FS}	Forward Transconductance	V_{DD} = 10 V, I_D = 9 A		43		S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 50 V, V_{GS} = 0 V, f = 1 MHz		968	1290	pF
C_{oss}	Output Capacitance			241	320	pF
C_{rss}	Reverse Transfer Capacitance			11	20	pF
R_g	Gate Resistance		0.1	0.6	2.5	Ω
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 50 V, I_D = 9 A, V_{GS} = 10 V, R_{GEN} = 6 Ω		9.7	19	ns
t_r	Rise Time			3.6	10	ns
$t_{d(off)}$	Turn-Off Delay Time			16	30	ns
t_f	Fall Time			3.4	10	ns
$Q_{g(TOT)}$	Total Gate Charge	V_{GS} = 0 V to 10 V; V_{DD} = 50 V, I_D = 9 A		15	22	nC
$Q_{g(TOT)}$	Total Gate Charge	V_{GS} = 0 V to 6 V; V_{DD} = 50 V, I_D = 9 A		9.8	15	nC
Q_{gs}	Total Gate Charge	V_{DD} = 50 V, I_D = 9 A		4.4		nC
Q_{gd}	Gate to Drain “Miller” Charge	V_{DD} = 50 V, I_D = 9 A		3.5		nC
Drain-Source Diode Characteristics						
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = 9 A (Note 2)		0.79	1.3	V
		V_{GS} = 0 V, I_S = 1.9 A (Note 2)		0.72	1.2	V
t_{rr}	Reverse Recovery Time	I_F = 9 A, di/dt = 100 A/μs		47	75	ns
Q_{rr}	Reverse Recovery Charge			45	73	nC

Notes:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 53 °C/W when mounted on a 1 in^2 pad of 2 oz copper



b. 125 °C/W when mounted on a minimum pad of 2 oz copper

2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.
3. E_{AS} of 181 mJ is based on starting T_J = 25 °C, L = 3 mH, I_{AS} = 11 A, V_{DD} = 100 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 35 A.
4. Pulse Id refers to Figure.11 Forward Bias Safe Operation Area.
5. Tested at I_D = 250 μA, V_{GS} = 0 V, V_{DS} is screened for 105 V minimum.

Typical Characteristics T_J = 25 °C unless otherwise noted

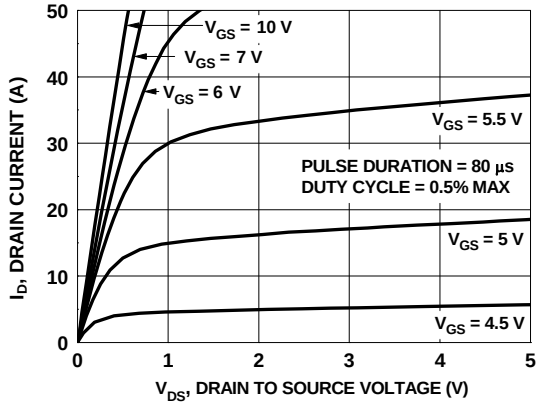


Figure 1. On-Region Characteristics

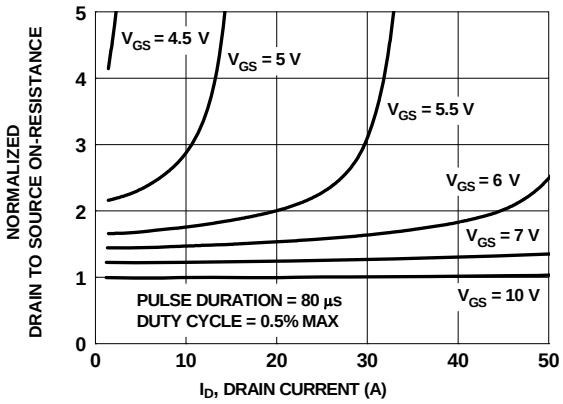


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

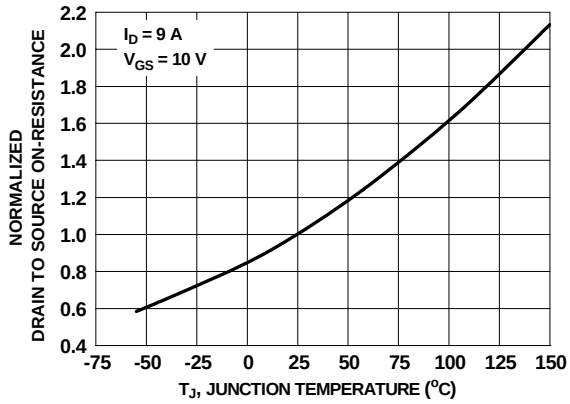


Figure 3. Normalized On-Resistance vs Junction Temperature

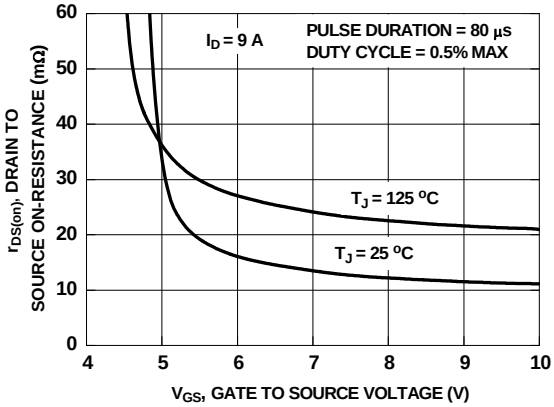


Figure 4. On-Resistance vs Gate to Source Voltage

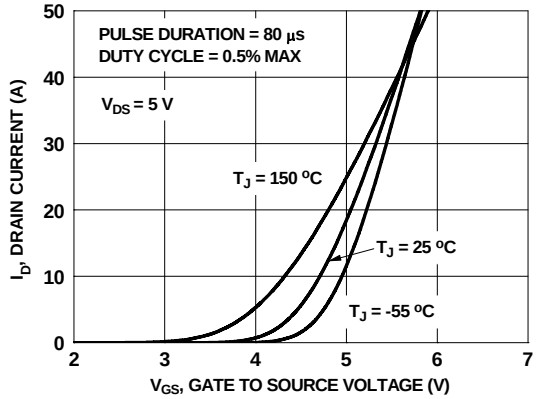


Figure 5. Transfer Characteristics

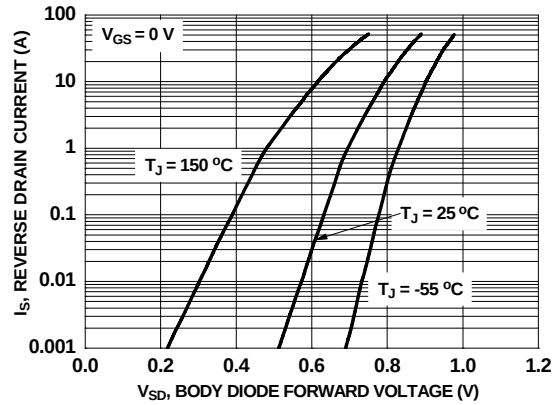


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

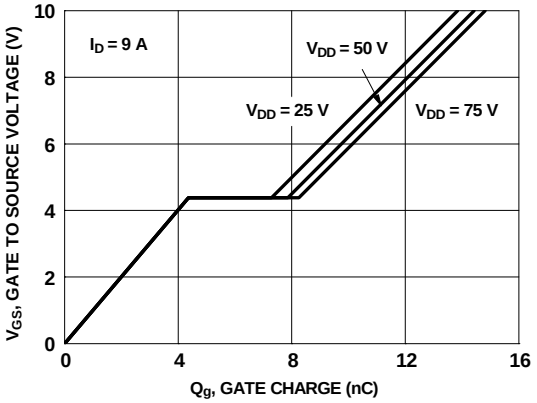


Figure 7. Gate Charge Characteristics

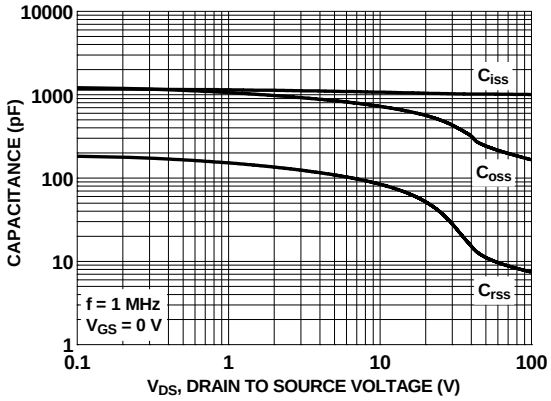


Figure 8. Capacitance vs Drain to Source Voltage

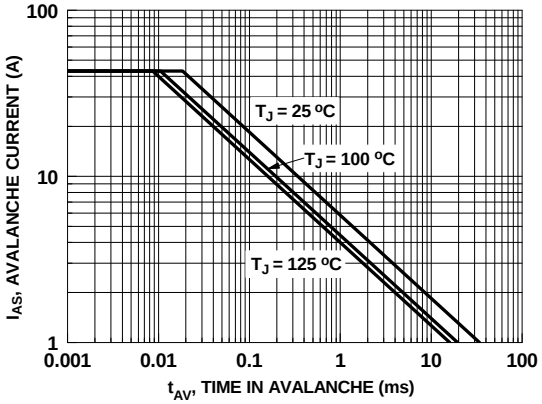


Figure 9. Unclamped Inductive Switching Capability

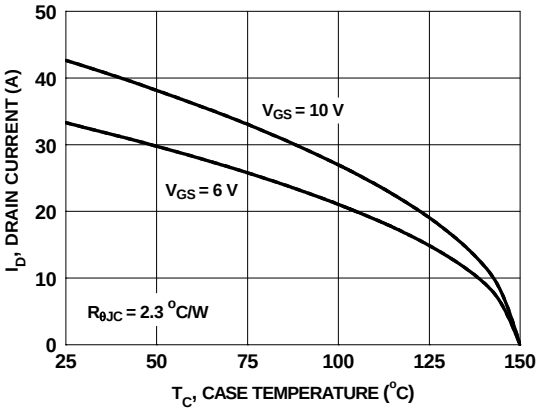


Figure 10. Maximum Continuous Drain Current vs Case Temperature

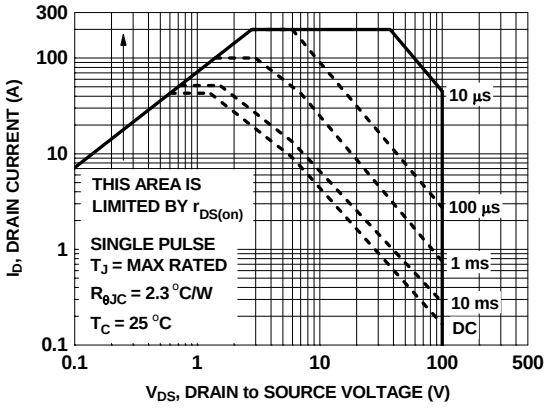


Figure 11. Forward Bias Safe Operating Area

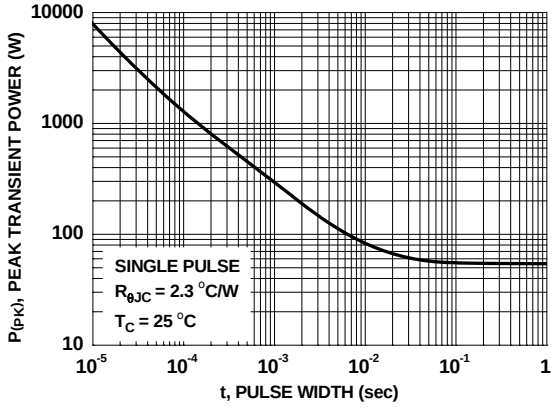


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

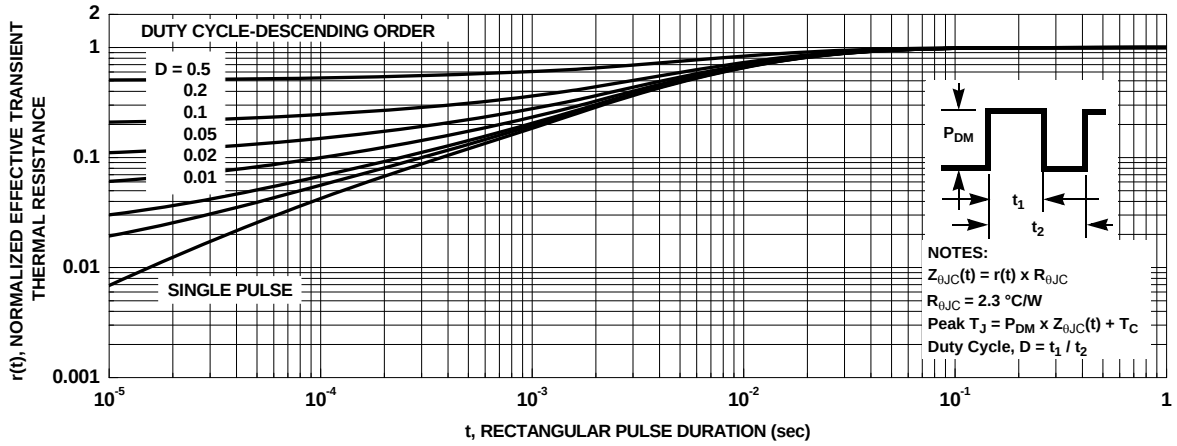
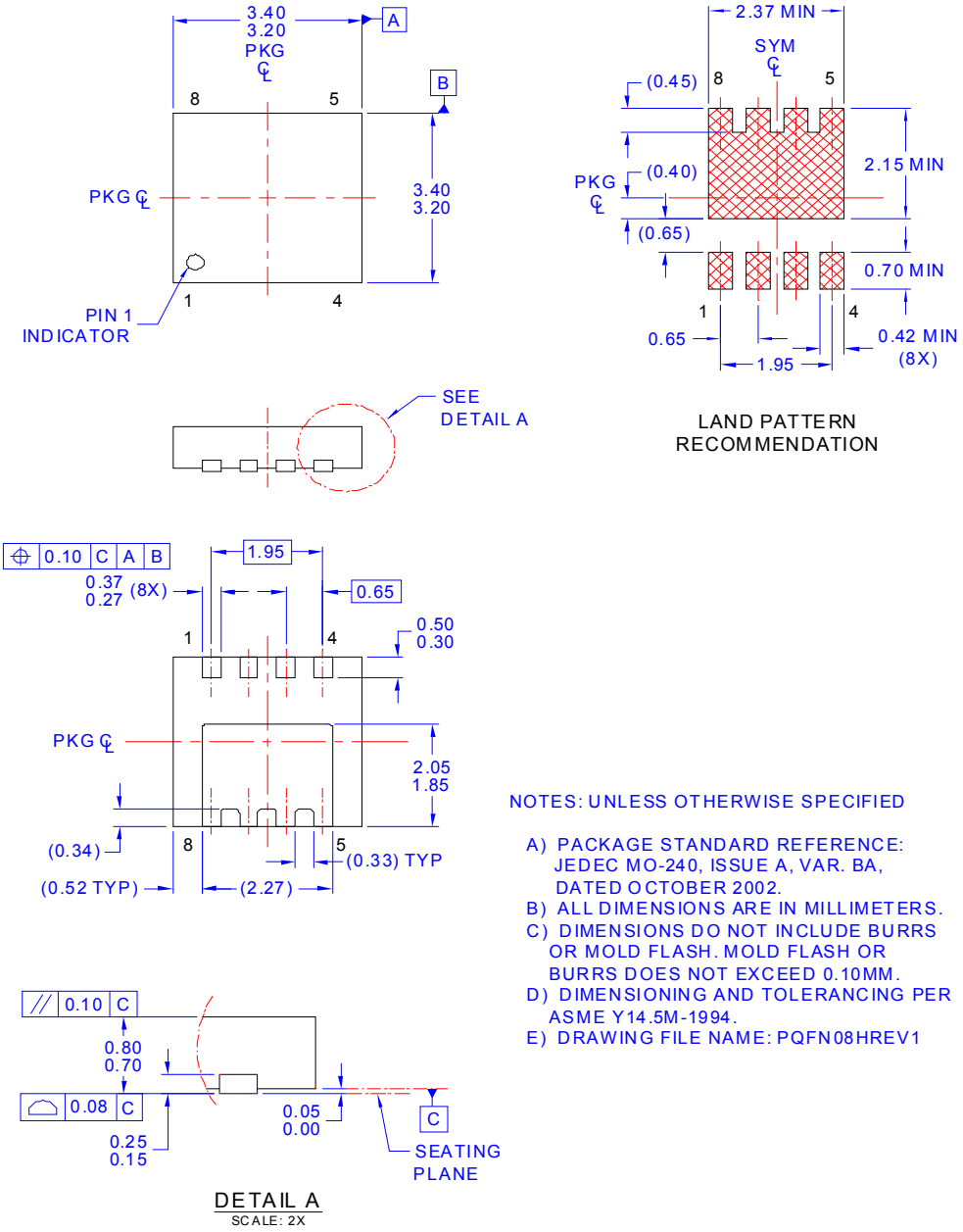


Figure 13. Junction-to-Case Transient Thermal Response Curve

Dimensional Outline and Pad Layout



NOTES: UNLESS OTHERWISE SPECIFIED

A) PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. BA, DATED OCTOBER 2002.
B) ALL DIMENSIONS ARE IN MILLIMETERS.
C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
E) DRAWING FILE NAME: PQFN08HREV1

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